

**Search Notes**

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10/647,893

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

NAKAMURA, SHINICHI

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	22,24,29 30,31,32 33	7/27/2006	SWH

**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

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